

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				SNDK.327US0		10/774,014	
				Applicant(s)		Conf. No.	
(Use several sheets if necessary)				Gerrit Jan Hemink		8419	
(Form PTO-1449)				Filing Date		Art Group	
				February 6, 2004		2827	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
MF	1	5,043,940	8/27/1991	Harari			
	2	5,172,338	12/15/1992	Mehrotra et al.			
	3	5,570,315	10/29/1996	Tanaka et al.			
	4	5,774,397	6/30/1998	Endoh et al.			
MF	5	5,887,145	3/23/1999	Harari et al.			
	6	6,046,935	4/4/2000	Takeuchi et al.			
	7	6,107,658	8/22/2000	Itoh et al.			
	8	6,456,528	9/24/2002	Chen			
	9	6,522,580	2/18/2003	Chen et al.			
MF	10	6,525,964	2/25/2003	Tanaka et al.			

U.S. Published Patent Application Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
MF	11	2003/0147278A1	8/7/2003	Tanaka et al.			

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
MF	12	Takaaki Nozaki et al., "A 1-Mb EEPROM with MONOS Memory Cell for Semiconductor Disk Application" IEEE Journal of Solid-State Circuits, Vol. 26, No. 4, April 1991, pp. 497-501.
	13	K. D. Suh et al. in "A 3.3 V 32 Mb NAND Flash Memory with Incremental Step Pulse Programming Scheme," Journal of Solid-State Circuits, Vol 30, No. 11, Nov. 1995, pp. 1149-55.
MF	14	T. S. Jung et al. proposed a local self boosting ("LSB") technique in "A 3.3V 128Mb Multi-Level NAND Flash Memory for Mass Storage Applications", ISSCC96, Session 2, Flash Memory, Paper TP 2.1, IEEE, pp. 32.

Examiner	MF	Date Considered	6/9/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.